

Power MOSFET

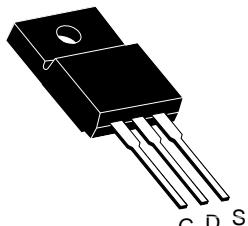
PRODUCT SUMMARY	
V _{DS} (V)	550
R _{DS(on)} max. at 25 °C (Ω)	V _{GS} = 10 V 0.30
Q _g max. (nC)	150
Q _{gs} (nC)	12
Q _{gd} (nC)	25
Configuration	Single

FEATURES

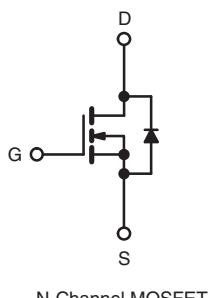
- Optimal Design
 - Low Area Specific On-Resistance
 - Low Input Capacitance (C_{iss})
 - Reduced Capacitive Switching Losses
 - High Body Diode Ruggedness
 - Avalanche Energy Rated (UIS)
- Optimal Efficiency and Operation
 - Low Cost
 - Simple Gate Drive Circuitry
 - Low Figure-of-Merit (FOM): R_{on} x Q_g
 - Fast Switching



TO-220 FULLPAK



Top View



APPLICATIONS

- Consumer Electronics
 - Displays (LCD or Plasma TV)
- Server and Telecom Power Supplies
 - SMPS
- Industrial
 - Welding
 - Induction Heating
 - Motor Drives
- Battery Chargers
- SMPS
 - Power Factor Correction (PFC)

ABSOLUTE MAXIMUM RATINGS (T_C = 25 °C, unless otherwise noted)

PARAMETER	SYMBOL	LIMIT	UNIT
Drain-Source Voltage	V _{DS}	550	V
Gate-Source Voltage		± 20	
Gate-Source Voltage AC (f > 1 Hz)		30	
Continuous Drain Current (T _J = 150 °C)	I _D	18	A
V _{GS} at 10 V		11	
T _C = 25 °C			
T _C = 100 °C			
Pulsed Drain Current ^a	I _{DM}	56	
Linear Derating Factor		2.2	W/°C
Single Pulse Avalanche Energy ^b	E _{AS}	281	mJ
Maximum Power Dissipation	P _D	60	W
Operating Junction and Storage Temperature Range	T _J , T _{stg}	- 55 to + 150	°C
Drain-Source Voltage Slope	dV/dt	24	V/ns
Reverse Diode dV/dt ^d		0.36	
Soldering Recommendations (Peak Temperature)	for 10 s	300 ^c	°C

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature.
- b. V_{DD} = 50 V, starting T_J = 25 °C, L = 10 mH, R_g = 25 Ω, I_{AS} = 7.5 A.
- c. 1.6 mm from case.
- d. I_{SD} ≤ I_D, starting T_J = 25 °C.

THERMAL RESISTANCE RATINGS				
PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R_{thJA}	-	40	
Maximum Junction-to-Case (Drain)	R_{thJC}	-	0.45	°C/W

SPECIFICATIONS ($T_J = 25$ °C, unless otherwise noted)							
PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static							
Drain-Source Breakdown Voltage	V_{DS}	$V_{GS} = 0$ V, $I_D = 250$ μA		550	-	-	V
V_{DS} Temperature Coefficient	$\Delta V_{DS}/T_J$	Reference to 25 °C, $I_D = 250$ μA		-	0.56	-	V/°C
Gate-Source Threshold Voltage (N)	$V_{GS(th)}$	$V_{DS} = V_{GS}$, $I_D = 250$ μA		2	-	4	V
Gate-Source Leakage	I_{GSS}	$V_{GS} = \pm 20$ V		-	-	± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 500$ V, $V_{GS} = 0$ V		-	-	1	
		$V_{DS} = 400$ V, $V_{GS} = 0$ V, $T_J = 125$ °C		-	-	10	μA
Drain-Source On-State Resistance	$R_{DS(on)}$	$V_{GS} = 10$ V	$I_D = 10$ A	-	-	0.30	Ω
Forward Transconductance	g_{fs}	$V_{DS} = 50$ V, $I_D = 10$ A		-	12	-	S
Dynamic							
Input Capacitance	C_{iss}	$V_{GS} = 0$ V, $V_{DS} = 100$ V, $f = 1$ MHz		-	3094	-	pF
Output Capacitance	C_{oss}			-	152	-	
Reverse Transfer Capacitance	C_{rss}			-	13	-	
Effective output capacitance, energy related ^a	$C_{o(er)}$	$V_{GS} = 0$ V, $V_{DS} = 0$ V to 400 V		-	131	-	
Effective output capacitance, time related ^b	$C_{o(tr)}$			-	189	-	
Total Gate Charge	Q_g	$V_{GS} = 10$ V	$I_D = 10$ A, $V_{DS} = 400$ V	-	80	150	nC
Gate-Source Charge	Q_{gs}			-	12	-	
Gate-Drain Charge	Q_{gd}			-	25	-	
Turn-On Delay Time	$t_{d(on)}$	$V_{DD} = 400$ V, $I_D = 10$ A, $V_{GS} = 10$ V, $R_g = 9.1$ Ω		-	24	50	ns
Rise Time	t_r			-	31	62	
Turn-Off Delay Time	$t_{d(off)}$			-	117	176	
Fall Time	t_f			-	56	112	
Gate Input Resistance	R_g	$f = 1$ MHz, open drain		-	1.8	-	Ω
Drain-Source Body Diode Characteristics							
Continuous Source-Drain Diode Current	I_S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	20	A
Pulsed Diode Forward Current	I_{SM}			-	-	80	
Diode Forward Voltage	V_{SD}	$T_J = 25$ °C, $I_S = 10$ A, $V_{GS} = 0$ V		-	-	1.2	V
Reverse Recovery Time	t_{rr}	$T_J = 25$ °C, $I_F = I_S = 10$ A, $dI/dt = 100$ A/μs, $V_R = 20$ V		-	437	-	ns
Reverse Recovery Charge	Q_{rr}			-	5.9	-	μC
Reverse Recovery Current	I_{RRM}			-	25	-	A

Notes

- a. $C_{oss(er)}$ is a fixed capacitance that gives the same energy as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DS} .
 b. $C_{oss(tr)}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DS} .

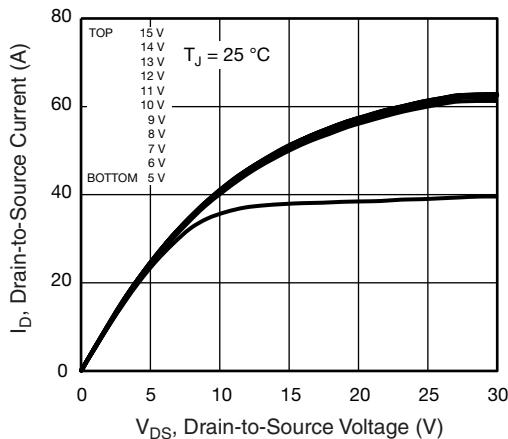
TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

Fig. 1 - Typical Output Characteristics

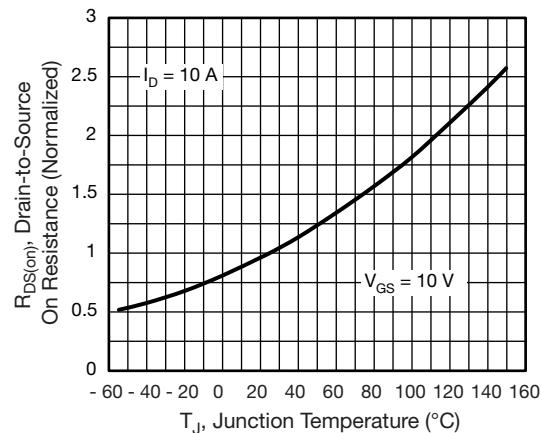


Fig. 4 - Normalized On-Resistance vs. Temperature

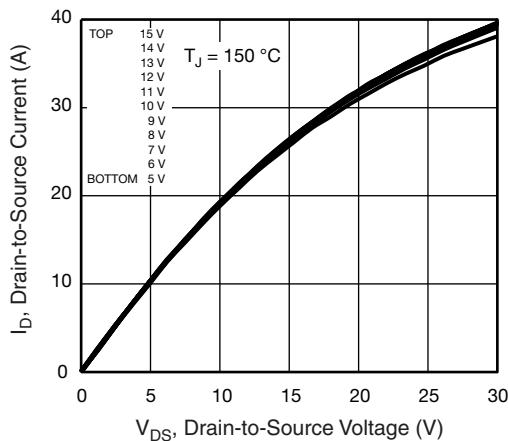


Fig. 2 - Typical Output Characteristics

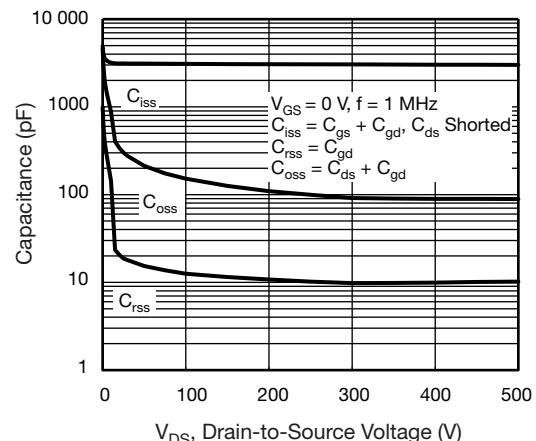


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

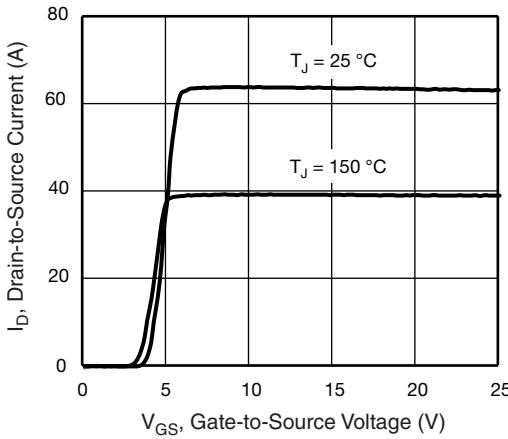


Fig. 3 - Typical Transfer Characteristics

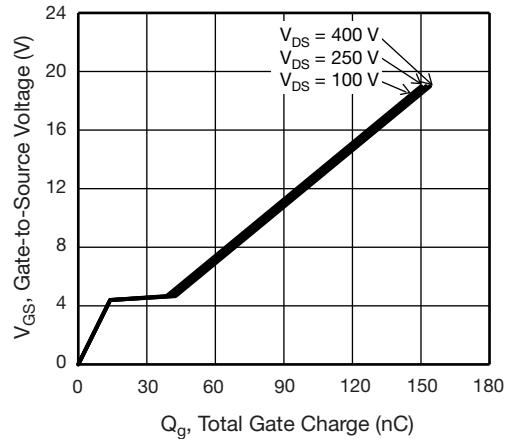


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

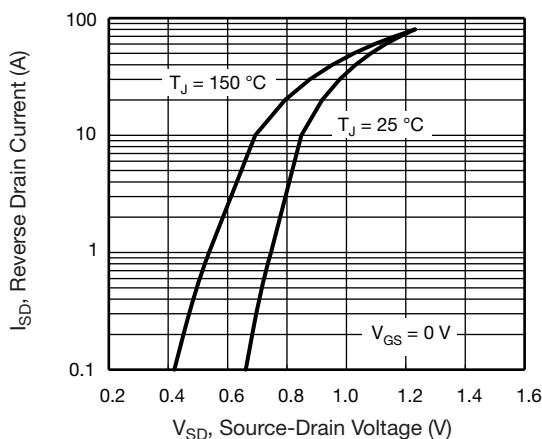


Fig. 7 - Typical Source-Drain Diode Forward Voltage

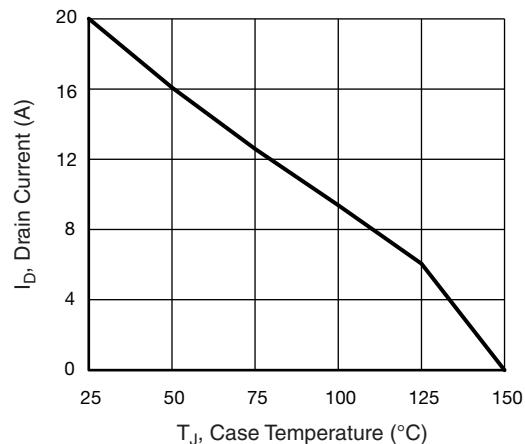


Fig. 9 - Maximum Drain Current vs. Case Temperature

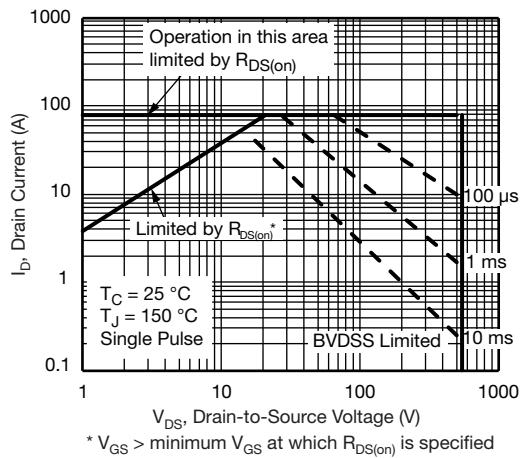


Fig. 8 - Maximum Safe Operating Area

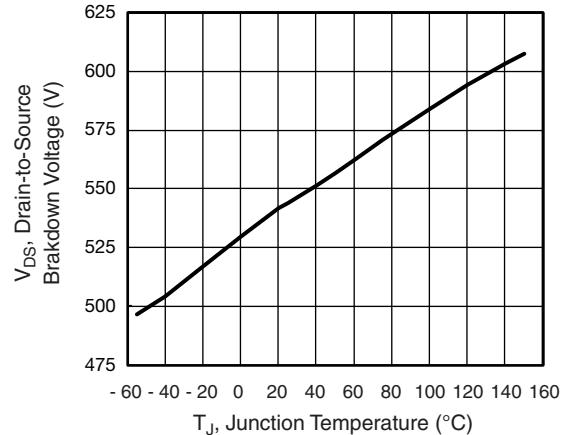


Fig. 10 - Temperature vs. Drain-to-Source Voltage

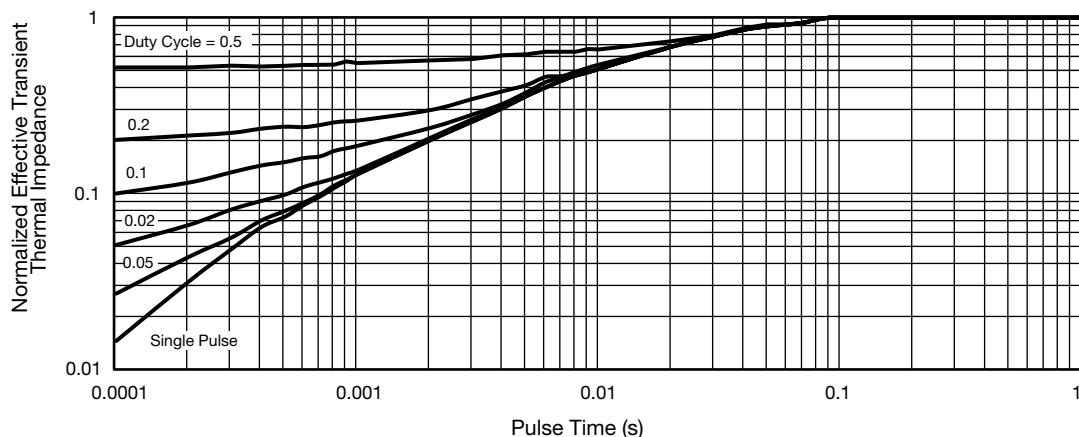


Fig. 11 - Normalized Thermal Transient Impedance, Junction-to-Case

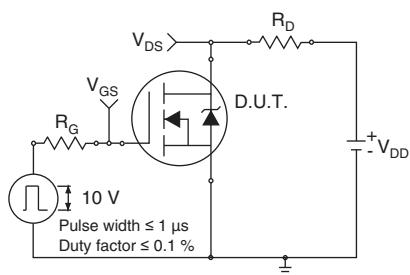


Fig. 12 - Switching Time Test Circuit

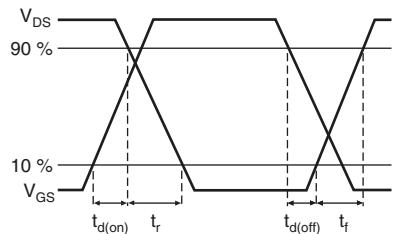


Fig. 13 - Switching Time Waveforms

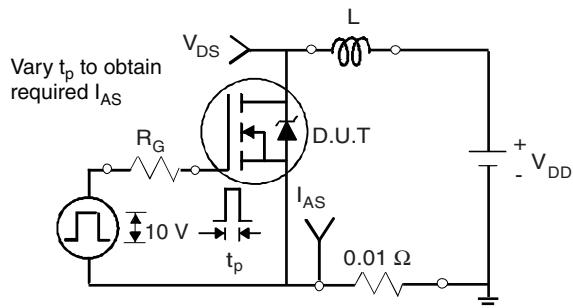


Fig. 14 - Unclamped Inductive Test Circuit

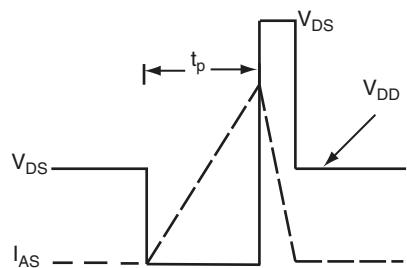


Fig. 15 - Unclamped Inductive Waveforms

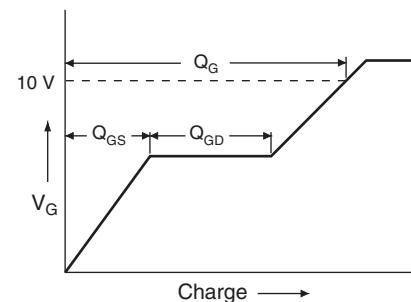


Fig. 16 - Basic Gate Charge Waveform

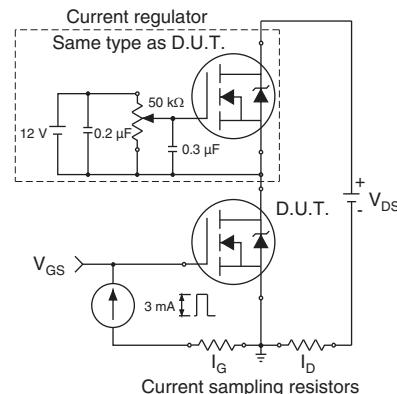
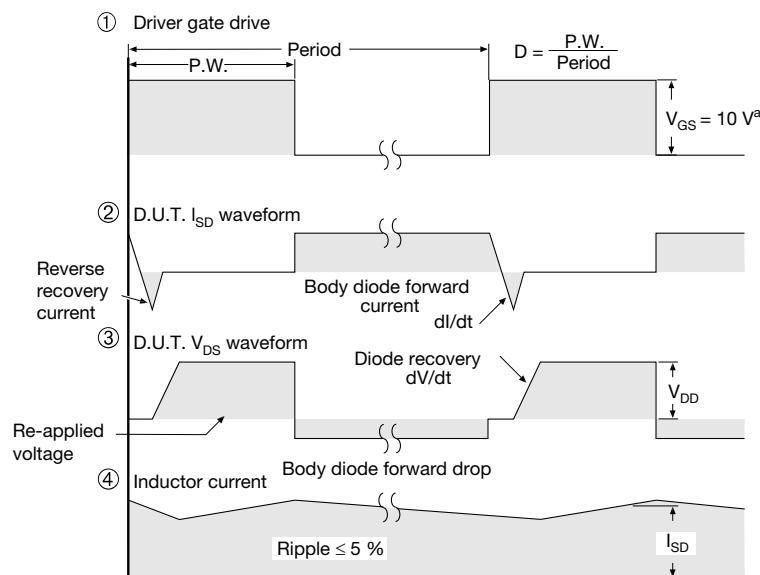
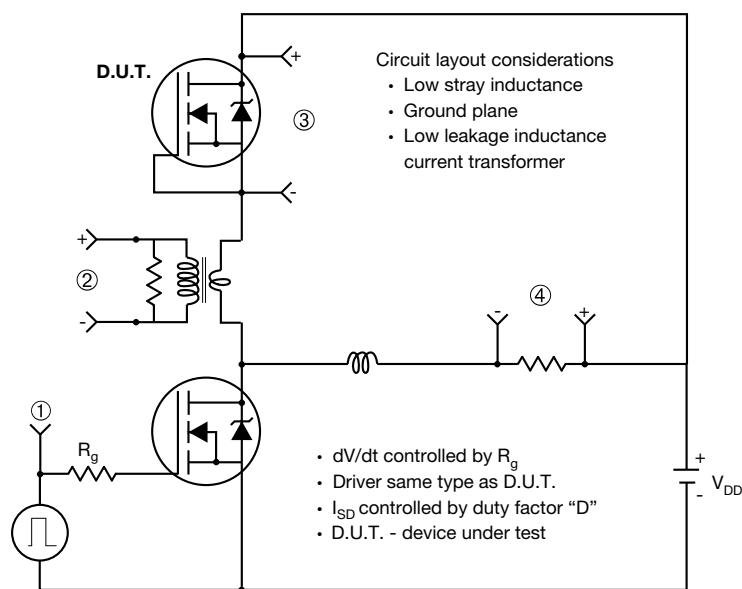


Fig. 17 - Gate Charge Test Circuit

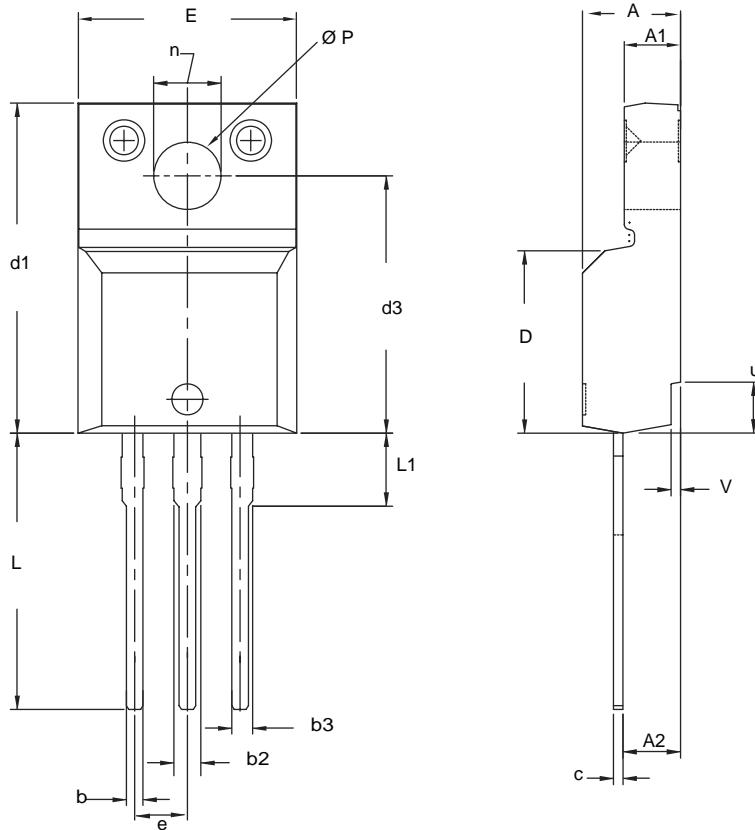
Peak Diode Recovery dV/dt Test Circuit



Note

a. $V_{GS} = 5 \text{ V}$ for logic level devices

Fig. 18 - For N-Channel

TO-220 FULLPAK (HIGH VOLTAGE)

DIM.	MILLIMETERS		INCHES	
	MIN.	MAX.	MIN.	MAX.
A	4.570	4.830	0.180	0.190
A1	2.570	2.830	0.101	0.111
A2	2.510	2.850	0.099	0.112
b	0.622	0.890	0.024	0.035
b2	1.229	1.400	0.048	0.055
b3	1.229	1.400	0.048	0.055
c	0.440	0.629	0.017	0.025
D	8.650	9.800	0.341	0.386
d1	15.88	16.120	0.622	0.635
d3	12.300	12.920	0.484	0.509
E	10.360	10.630	0.408	0.419
e	2.54 BSC		0.100 BSC	
L	13.200	13.730	0.520	0.541
L1	3.100	3.500	0.122	0.138
n	6.050	6.150	0.238	0.242
Ø P	3.050	3.450	0.120	0.136
u	2.400	2.500	0.094	0.098
v	0.400	0.500	0.016	0.020

ECN: X09-0126-Rev. B, 26-Oct-09
DWG: 5972

Notes

1. To be used only for process drawing.
2. These dimensions apply to all TO-220, FULLPAK leadframe versions 3 leads.
3. All critical dimensions should C meet $C_{pk} > 1.33$.
4. All dimensions include burrs and plating thickness.
5. No chipping or package damage.

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